

	Type	Hits	Search Text	DBs
1	IS&R	4	(("6043672") or ("6313656")).PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB
2	BRS	0	"438"/\$.ccls. and (conductive adj force adj microscope)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
3	BRS	0	438/17 and (conductive adj force adj microscope)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
4	BRS	0	"438"/\$.ccls. and (conductive adj force adj microscope)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
5	BRS	0	"438"/\$.ccls. and (conductive adj force adj microscope)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
6	BRS	0	"324"/\$.ccls. and (conductive adj force adj microscope)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
7	BRS	2	"324"/\$.ccls. and (conductive adj atomic adj force adj microscope)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
8	IS&R	2	((5585734)).PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB
9	BRS	0	((5585734)).PN.) and (leakage adj current)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
10	BRS	1883	"324"/\$.ccls. and (leakage adj current)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
11	BRS	1	((324"/\$.ccls. and (leakage adj current)) and (measuring adj leakage adj current)) and (conductive adj atomic force adj microscope)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
12	BRS	120	((324"/\$.ccls. and (leakage adj current)) and (measuring adj leakage adj current))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB

	Type	Hits	Search Text	DBs
13	IS&R	2	("20030057988").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB
14	IS&R	2	("6147507").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB
15	BRS	113	"324"/\$.ccls. and (tunneling adj microscope)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB
16	BRS	3	"324"/\$.ccls. and (conductive adj atomic adj force adj microscope)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB